

Manual Supplement

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This supplement contains information necessary to ensure the accuracy of the above manual.

Change #1, 579

On page 74, under **General Specifications**, add the following under the Electromagnetic Compatibility (EMC)

Some mobile devices that transmit RF energy may transmit levels that far exceed 3 V/m and may damage sensitive electronic circuits. To insure the best performance, do not allow a device which is transmitting RF energy in excess of 3 V/m to be within 30 cm of the Tester while in use.

Change #2, 594

On page 84, replace the **Test Signals** table with:

Test Signals

RCD Type	Test Signal Description
AC (sinusoidal)	The waveform is a sinewave starting at zero crossing, polarity determined by phase selection (0 ° phase starts with low to high zero crossing, 180 ° phase starts with high to low zero crossing). The magnitude of the test current is $I_{\Delta n} \times \text{Multiplier}$ for all tests.
A (half wave)	The waveform is a half wave rectified sinewave starting at zero, polarity determined by phase selection (0 ° phase starts with low to high zero crossing, 180 ° phase starts with high to low zero crossing). The magnitude of the test current is $0.7 \times I_{\Delta n} \text{ (rms)} \times \text{Multiplier}$ for all tests where the multiplier is $\times 0.5$ ($\times 1/2$). The magnitude of the test current is $2.0 \times I_{\Delta n} \text{ (rms)} \times \text{Multiplier}$ for all tests where both the multiplier is $\geq \times 1$ and $I_{\Delta n} = 0.01\text{A}$. The magnitude of the test current is $1.4 \times I_{\Delta n} \text{ (rms)} \times \text{Multiplier}$ for all tests for all other settings.
B (DC)	This is a smooth DC current according to EN61557-6 Annex A

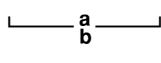
Change #3, 426

On page 63, replace the **Memory Mode** section with:

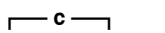
Memory Mode

You can store up to 3000 measurements on the Tester. The information stored for each measurement consists of the test function and all user selectable test conditions.


The location identifier includes a location set number (a), location subset number (b), and location ID number (c). You can store multiple measurements to the same memory location (a, b, c) and view later with the Tester or a software program such as Fluke DMS Software. With DMS you have additional tools to apply custom labels to these memory locations. See the *DMS Software User Manual* for more information.

 Use the location set field (a) to indicate a site reference number.

Use the location subset field (b) to indicate a location such as a room or electrical panel number.

 Use the location ID field (c) for circuit number.

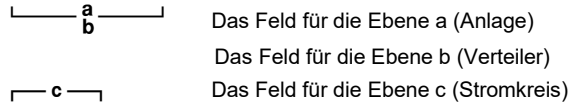
To enter Memory mode:

1. Press  to enter Memory mode. See Figure **Error! Reference source not found.**

On page 63 in the German manual, replace the **Speichermodus**, section with:

Speichermodus

Es können bis zu 3.000 Messungen im Tester gespeichert werden. Die für jede Messung gespeicherten Informationen umfassen die Messfunktion und alle Messparameter, die der Bediener auswählen kann. Der Standortbezeichner inkludiert eine Nummer für die Ebene a (Anlage), die Ebene b (Verteiler) und die Ebene c (Stromkreis). Sie können mehrere Messwerte auf derselben Speicherposition (a, b, c) speichern und später mit dem Tester oder einem Softwareprogramm wie Fluke DMS anzeigen. DMS bietet Ihnen zusätzliche Tools, um diesen Speicherpositionen benutzerdefinierte Kennungen zuzuweisen. Weitere Informationen finden Sie im *Bedienungshandbuch zur DMS Software*.



Aktivieren des Speichermodus:

1. **MEMORY** drücken, um den Speichermodus zu aktivieren. Siehe Abbildung 15.

Change #4, 692

On page 12, **Table 6**, replace number ⑥ with:

⑥		Turn on and turn off the backlight. Hold 1 second to get into IT mode selection.
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On page 20, **Table 10**, replace the second row with:

① F2	IT mode toggle	IT mode toggle In IT mode, a loop test or an RCD test is allowed even if the voltage N-PE is higher than 25 V / 50 V. The default setting is IT OFF. See page 12, number ⑥, for IT mode selection.
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On page 35, Table 14, replace the first row with:

F1	Input section: N PE L N PE L	•	•	•
F1	Input select for IT mode: N PE L	•	•	•



On page 36, replace the Note, with:

Note

Errors may occur due to equipment on the circuit under test. If the measurement is too noisy, "Err5" will alternate with the measured value. Pressing the key will show the available readings in the secondary display. If the Tester shows 0.00 Ω, consider that no perfect circuit exists. Check for correct leads connection to instrument, leads are zeroed, and fuse is good.

On page 39, under **Loop Impedance in IT System Measurement**, replace the paragraph and Figure 6 with:

Select IT mode with the power up option or use the backlight key on the front panel:

- Press the backlight key for 1 second to see the IT mode status.
- Use the   arrow key to toggle On/Off for IT mode.
- L-PE loop measurement not available in NT loop during IT mode.

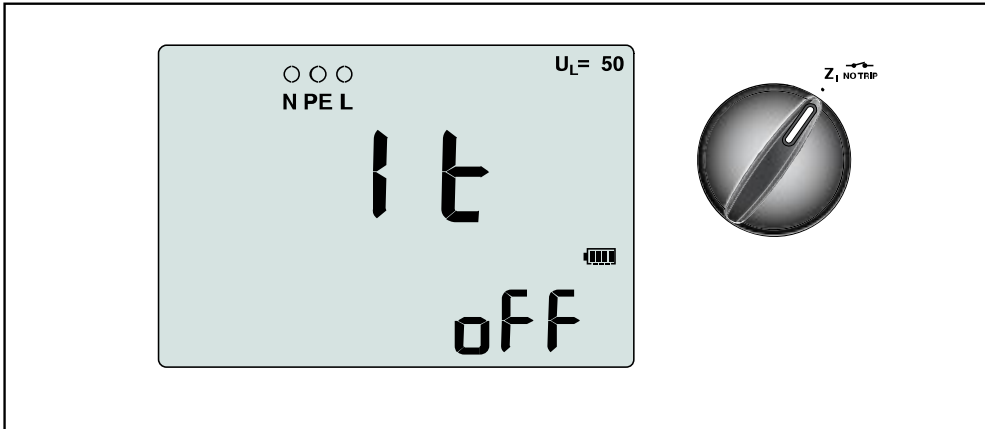


Figure 6. Loop Impedance Test in IT System

On page 53, replace the second paragraph with:

To test an RCD at the mains socket, put the Tester into the IT mode. In this mode the Tester accepts any voltage between N and PE. The precondition for trip time and current measurements is that the resistance of the earth ground system is low enough to allow the test current to flow.